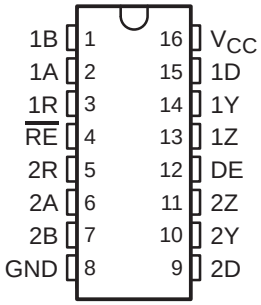
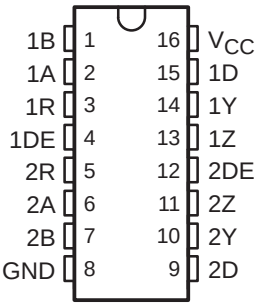
- **Meet or Exceed the Requirements of ANSI Standards TIA/EIA-422-B and TIA/EIA-485-A and ITU Recommendations V.10 and V.11**
- **Designed for Multipoint Bus Transmission on Long Bus Lines in Noise Environments**
- **Driver Positive- and Negative-Current Limiting**
- **Thermal Shutdown Protection**
- **Driver 3-State Outputs**
- **Receiver Common-Mode Input Voltage Range of –12 V to 12 V**
- **Receiver Input Sensitivity . . . ±200 mV**
- **Receiver Hysteresis . . . 50 mV Typ**
- **Receiver Input Impedance . . . 12 kΩ Min**
- **Receiver 3-State Outputs (SN751177 Only)**
- **Operate From Single 5-V Supply**

SN751177 . . . N OR NS† PACKAGE
(TOP VIEW)



SN751178 . . . N OR NS† PACKAGE
(TOP VIEW)



† The NS package is only available taped and reeled.

description

The SN751177 and SN751178 dual differential drivers and receivers are monolithic integrated circuits that are designed for balanced multipoint bus transmission at rates up to 10 Mbit/s. They are designed to improve the performance of full-duplex data communications over long bus lines and meet ANSI Standards TIA/EIA-422-B and TIA/EIA-485-A and ITU Recommendations V.10 and V.11.

The SN751177 and SN751178 driver outputs provide limiting for both positive and negative currents and thermal-shutdown protection from line fault conditions on the transmission bus line.

The receiver features high input impedance of at least 12 kΩ, an input sensitivity of ±200 mV over a common-mode input voltage range of –12 V to 12 V and typical input hysteresis of 50 mV. Fail-safe design ensures that if the receiver inputs are open, the receiver outputs always will be high.

The SN751177 and SN751178 are characterized for operation from –20°C to 85°C.

Function Tables

SN751177, SN751178
(each driver)

INPUT D	ENABLE DE	OUTPUTS	
		Y	Z
H	H	H	L
L	H	L	H
X	L	Z	Z

H = high level, L = low level, X = irrelevant,
Z = high impedance (off)

SN751177
(each receiver)

DIFFERENTIAL INPUTS A – B	ENABLE $\overline{RE}$	OUTPUT R
$V_{ID} \geq 0.2$ V	L	H
–0.2 V < V_{ID} < 0.2 V	L	?
$V_{ID} \leq$ –0.2 V	L	L
X	H	Z
Open	L	H

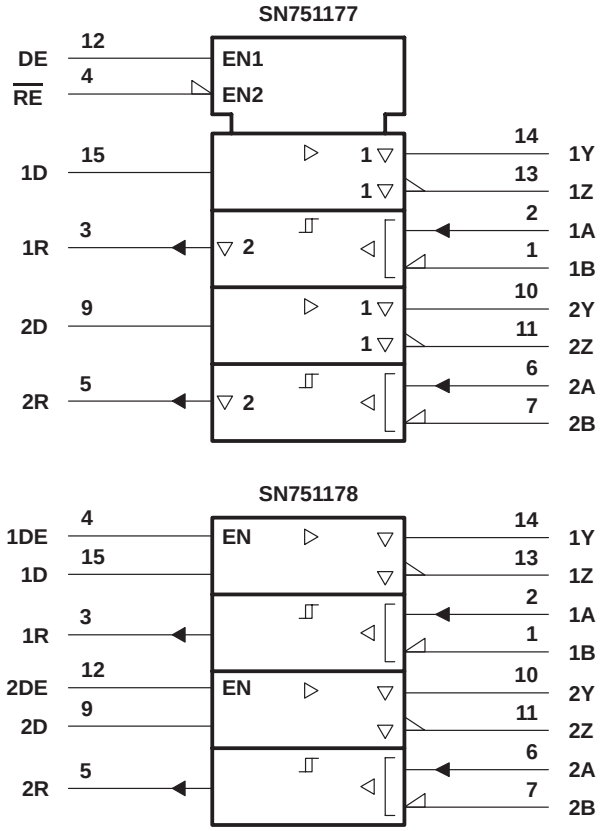
H = high level, L = low level, ? = indeterminate,
X = irrelevant, Z = high impedance (off)

SN751178
(each receiver)

DIFFERENTIAL INPUTS A – B	OUTPUT R
$V_{ID} \geq 0.2$ V	H
–0.2 V < V_{ID} < 0.2 V	?
$V_{ID} \leq$ –0.2 V	L

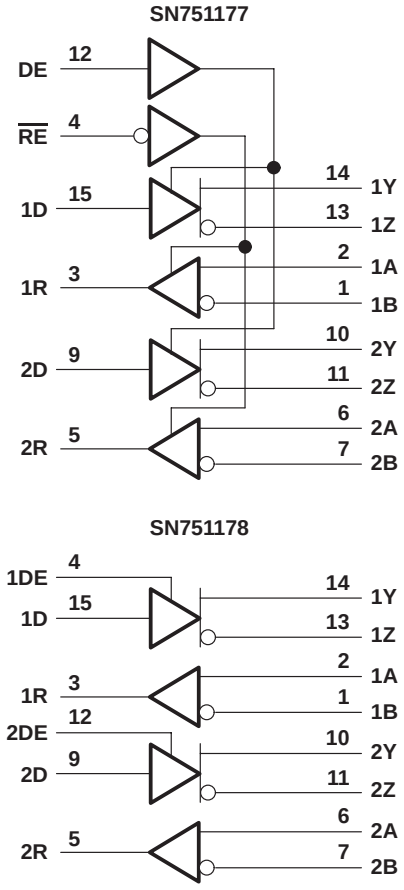
H = high level, L = low level,
? = indeterminate

logic symbols†

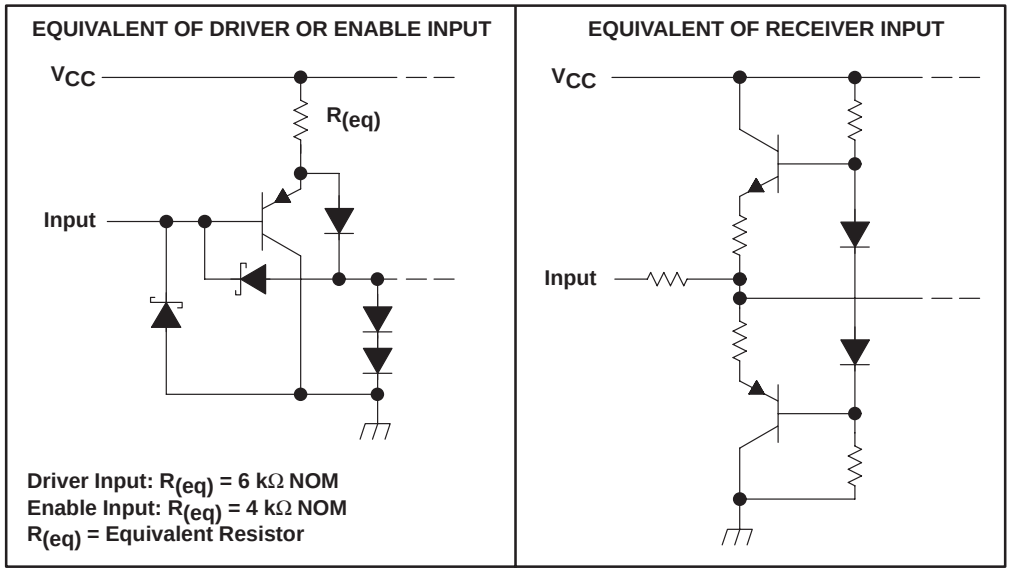


† These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagrams (positive logic)

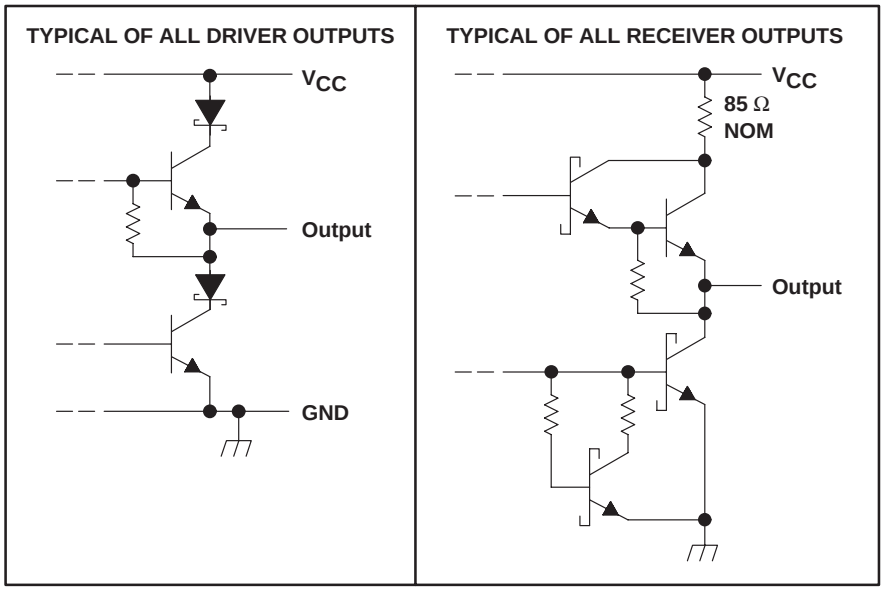


schematics of inputs



All resistor values are nominal.

schematics of outputs



All resistor values are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage, V_I (DE, $\overline{RE}$, and D inputs)	7 V
Receiver input voltage range, V_I (A or B inputs)	–25 V to 25 V
Receiver differential input voltage range, V_{ID} (see Note 2)	–25 V to 25 V
Driver output voltage range, V_O	–10 V to 15 V
Receiver low-level output current, I_{OL}	50 mA
Package thermal impedance, θ_{JA} (see Note 3): N package	78°C/W
NS package	111°C/W
Storage temperature range, T_{stg}	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values, except differential input voltage, are with respect to the network ground terminal.
2. Differential input voltage is measured at the noninverting terminal with respect to the inverting terminal.
3. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V_{CC}		4.75	5	5.25	V
High-level input voltage, V_{IH}	DE, $\overline{RE}$, and D inputs	2			V
Low-level input voltage, V_{IL}				0.8	V
Common-mode output voltage, V_{OC}	Driver	–7†		12	V
High-level output current, I_{OH}				–60	mA
Low-level output current, I_{OL}				60	mA
Common-mode input voltage, V_{IC}	Receiver			±12	V
Differential input voltage, V_{ID}				±12	V
High-level output current, I_{OH}				–400	µA
Low-level output current, I_{OL}				16	mA
Operating free-air temperature, T_A		–20		85	°C

† The algebraic convention, where the less positive (more negative) limit is designated as minimum, is used in this data sheet for common-mode output and threshold voltage levels only.

DRIVER SECTIONS

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS			MIN	TYP†	MAX	UNIT
V_{IK}	Input clamp voltage	I_I = –18 mA					–1.5	V
V_{OH}	High-level output voltage	V_{IH} = 2 V,	V_{IL} = 0.8 V,	I_{OH} = –33 mA		3.7		V
V_{OL}	Low-level output voltage	V_{IH} = 2 V,	V_{IL} = 0.8 V,	I_{OH} = 33 mA		1.1		V
$\|V_{OD1}\|$	Differential output voltage	I_O = 0			1.5		6	V
$\|V_{OD2}\|$	Differential output voltage	R_L = 100 Ω,	See Figure 1		2			V
					1/2 V_{OD1}			
		R_L = 54 Ω,	See Figure 1		1.5		5	
V_{OD3}	Differential output voltage	See Note 4			1.5		5	V
$\Delta\|V_{OD}\|$	Change in magnitude of differential output voltage (see Note 5)	R_L = 54 Ω or 100 Ω,		See Figure 1			±0.2	V
V_{OC}	Common-mode output voltage				–1‡		3	V
$\Delta\|V_{OC}\|$	Change in magnitude of common-mode output voltage (see Note 5)						±0.2	V
I_O	Output current with power off	V_{CC} = 0,	V_O = –7 V to 12 V				±100	µA
I_{OZ}	High-impedance-state output current	V_O = –7 V to 12 V					±100	µA
I_{IH}	High-level input current	V_{IH} = 2.7 V					20	µA
I_{IL}	Low-level input current	V_{IL} = 0.4 V					–100	µA
I_{OS}	Short-circuit output current (see Note 6)	V_O = –7 V					–250	mA
		V_O = V_{CC}					250	
		V_O = 12 V					250	
I_{CC}	Supply current	No load	Outputs enabled			80	110	mA
			Outputs disabled			50	80	

† All typical values are at V_{CC} = 5 V and T_A = 25°C.
‡ The algebraic convention, where the less positive (more negative) limit is designated as minimum, is used in this data sheet for common-mode output and threshold voltage levels only.

NOTES: 4. See TIA/EIA-485-A Figure 3.5, Test Termination Measurement 2
5. $\Delta|V_{OD}|$ and $\Delta|V_{OC}|$ are the changes in magnitude of V_{OD} and V_{OC}, respectively, that occur when the input is changed from a high level to a low level.
6. Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

switching characteristics at V_{CC} = 5 V, C_L = 50 pF, T_A = 25°C

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{d(OD)}$	Differential output delay time	R_L = 54 Ω,	See Figure 3		20	25	ns
$t_{t(OD)}$	Differential output transition time				27	35	ns
t_{PLH}	Propagation delay time, low- to high-level output	R_L = 27 Ω,	See Figure 4		20	25	ns
t_{PHL}	Propagation delay time, high- to low-level output				20	25	ns
t_{PZH}	Output enable time to high level	R_L = 110 Ω,	See Figure 5		80	120	ns
t_{PZL}	Output enable time to low level	R_L = 110 Ω,	See Figure 6		40	60	ns
t_{PHZ}	Output disable time from high level	R_L = 110 Ω,	See Figure 5		90	120	ns
t_{PLZ}	Output disable time from low level	R_L = 110 Ω,	See Figure 6		30	45	ns

SYMBOL EQUIVALENTS

DATA-SHEET PARAMETER	TIA/EIA-422-B	TIA/EIA-485-A
$\lvert V_{OD1}\rvert$	V_O	V_O
$\lvert V_{OD2}\rvert$	V_t (R_L = 100 Ω)	V_t (R_L = 54 Ω)
$\lvert V_{OD3}\rvert$		V_t (Test Termination Measurement 2)
$\Delta\lvert V_{OD}\rvert$	$\lvert \lvert V_t\rvert - \lvert \overline{V}_t\rvert \rvert$	$\lvert \lvert V_t\rvert - \lvert \overline{V}_t\rvert \rvert$
V_{OC}	$\lvert V_{OS}\rvert$	$\lvert V_{OS}\rvert$
$\Delta\lvert V_{OC}\rvert$	$\lvert V_{OS} - \overline{V}_{OS}\rvert$	$\lvert V_{OS} - \overline{V}_{OS}\rvert$
I_{OS}	$\lvert I_{sa}\rvert$, $\lvert I_{sb}\rvert$	
I_O	$\lvert I_{xa}\rvert$, $\lvert I_{xb}\rvert$	I_{ia}, I_{ib}

RECEIVER SECTIONS

electrical characteristics over recommended ranges of common-mode input voltage, supply voltage, and operating free-air temperature (unless otherwise noted)

PARAMETER			TEST CONDITIONS		MIN	TYP†	MAX	UNIT
V_{IT+}	Positive-going input threshold voltage		V_O = 2.7 V,	I_O = –0.4 mA			0.2	V
$V_{IT–}$	Negative-going input threshold voltage		V_O = 0.5 V,	I_O = 16 mA	–0.2‡			V
V_{hys}	Input hysteresis voltage ($V_{IT+} – V_{IT–}$)					50		mV
V_{IK}	Enable clamp voltage	SN751177	I_I = –18 mA				–1.5	V
V_{OH}	High-level output voltage		V_{ID} = 200 mV,	I_{OH} = –400 μA	2.7			V
V_{OL}	Low-level output voltage		V_{ID} = –200 mV	I_{OL} = 8 mA			0.45	V
				I_{OL} = 16 mA			0.5	
I_{OZ}	High-impedance-state output current	SN751177	V_O = 0.4 V to 2.4 V				±20	μA
I_I	Line input current (see Note 7)		Other input at 0 V	V_I = 12 V			1	mA
				V_I = –7 V			–0.8	
I_{IH}	High-level enable input current	SN751177	V_{IH} = 2.7 V				20	μA
I_{IL}	Low-level enable input current	SN751177	V_{IL} = 0.4 V				–100	μA
I_{OS}	Short-circuit output current (see Note 6)				–15		–85	μA
I_{CC}	Supply current		No load,	Outputs enabled		80	110	mA
r_i	Input resistance				12			kΩ

† All typical values are at V_{CC} = 5 V and T_A = 25°C.

‡ The algebraic convention, where the less positive (more negative) limit is designated as minimum, is used in this data sheet for common-mode output and threshold voltage levels only.

NOTES: 6. Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

7. Refer to ANSI Standards TIA/EIA-422-B, TIA/EIA-423-A, and TIA/EIA-485-A for exact conditions.

switching characteristics at V_{CC} = 5 V, C_L = 15 pF, T_A = 25°C

PARAMETER			TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{PLH}	Propagation delay time, low- to high-level output		V_{ID} = –1.5 V to 1.5 V, See Figure 7		20	35	ns
t_{PHL}	Propagation delay time, high- to low-level output				22	35	ns
t_{PZH}	Output enable time to high level	SN751177	See Figure 8		17	25	ns
t_{PZL}	Output enable time to low level				20	27	ns
t_{PHZ}	Output disable time from high level				25	40	ns
t_{PLZ}	Output disable time from low level				30	40	ns

PARAMETER MEASUREMENT INFORMATION

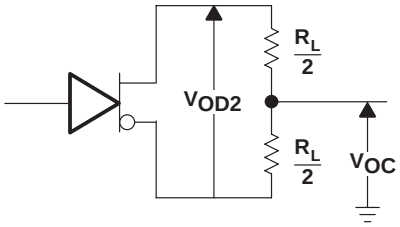


Figure 1. Driver Test Circuit, V_{OD} and V_{OC}

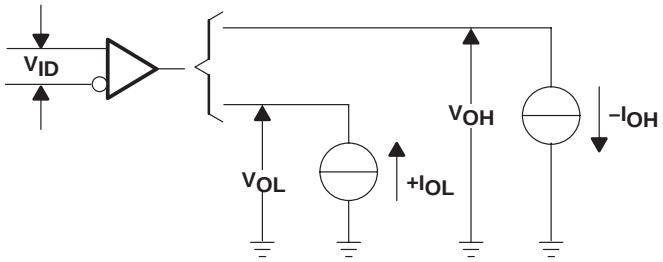
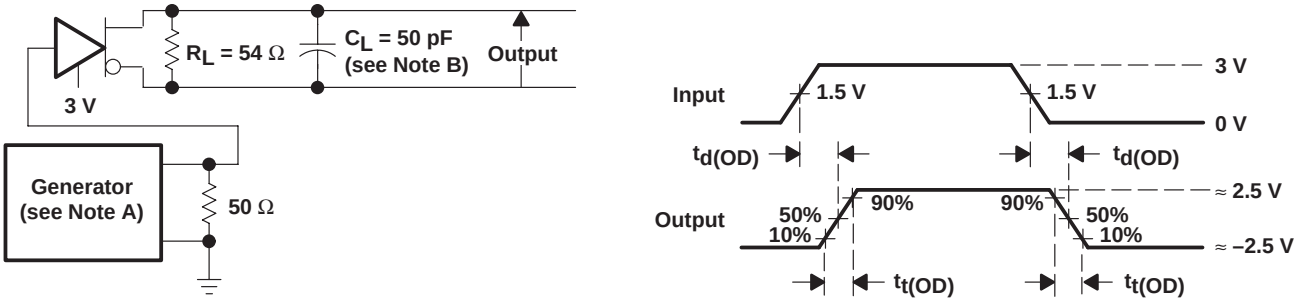


Figure 2. Receiver Test Circuit, V_{OH} and V_{OL}

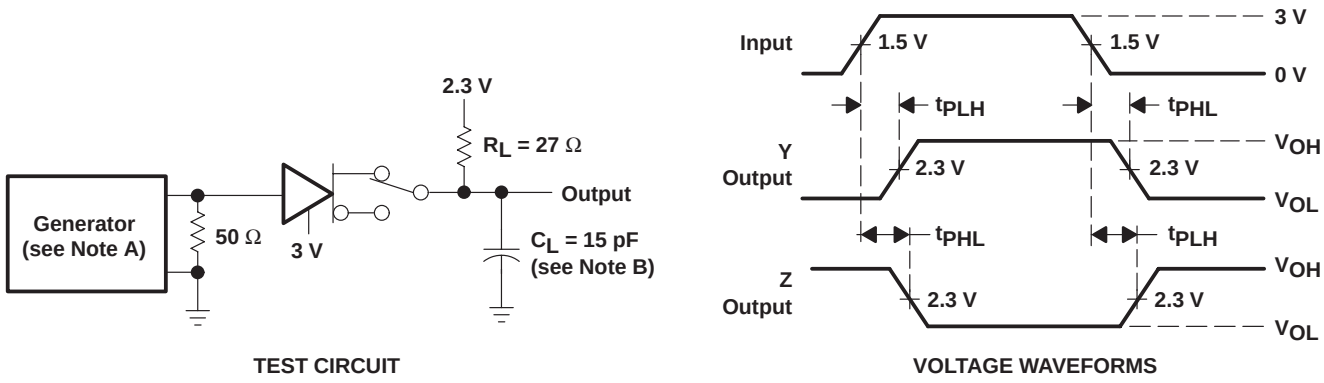


TEST CIRCUIT **VOLTAGE WAVEFORMS**

NOTES: A. The pulse generator has the following characteristics: PRR ≤ 1 MHz, 50% duty cycle, Z_O = 50 Ω, t_r ≤ 6 ns, t_f ≤ 6 ns.
B. C_L includes probe and jig capacitance.

Figure 3. Driver Differential Output-Delay and Transition-Time Test Circuit and Voltage Waveforms

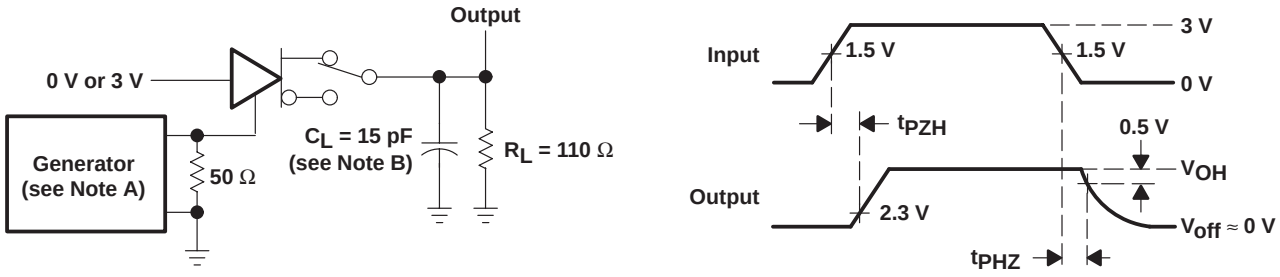
PARAMETER MEASUREMENT INFORMATION



TEST CIRCUIT VOLTAGE WAVEFORMS

NOTES: A. The pulse generator has the following characteristics: PRR ≤ 1 MHz, 50% duty cycle, Z_O = 50 Ω, t_r ≤ 6 ns, t_f ≤ 6 ns.
B. C_L includes probe and jig capacitance.

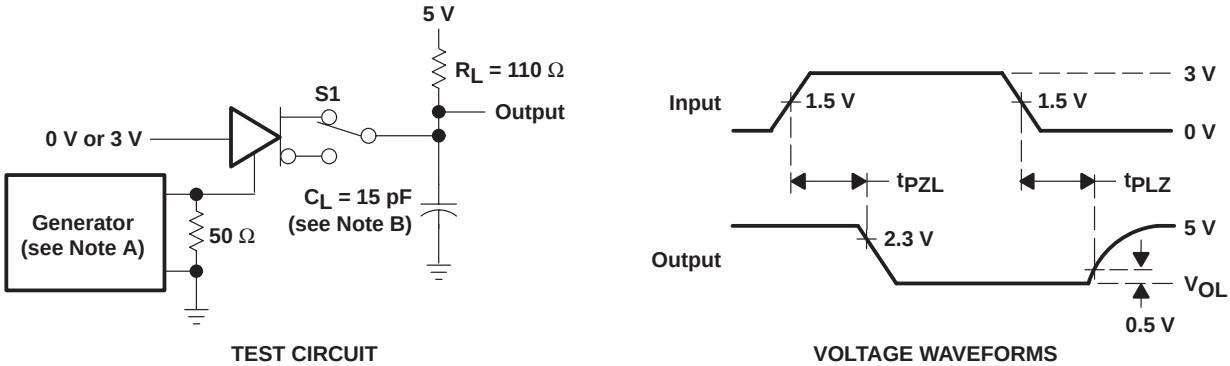
Figure 4. Driver Propagation Delay Time Test Circuit and Voltage Waveforms



TEST CIRCUIT VOLTAGE WAVEFORMS

NOTES: A. The pulse generator has the following characteristics: PRR ≤ 1 MHz, 50% duty cycle, Z_O = 50 Ω, t_r ≤ 6 ns, t_f ≤ 6 ns.
B. C_L includes probe and jig capacitance.

Figure 5. Driver Enable- and Disable-Time Test Circuit and Voltage Waveforms

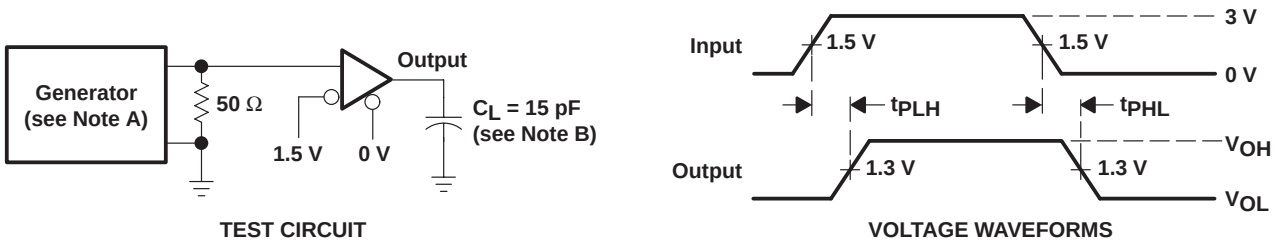


TEST CIRCUIT VOLTAGE WAVEFORMS

NOTES: A. The pulse generator has the following characteristics: PRR ≤ 1 MHz, 50% duty cycle, Z_O = 50 Ω, t_r ≤ 6 ns, t_f ≤ 6 ns.
B. C_L includes probe and jig capacitance.

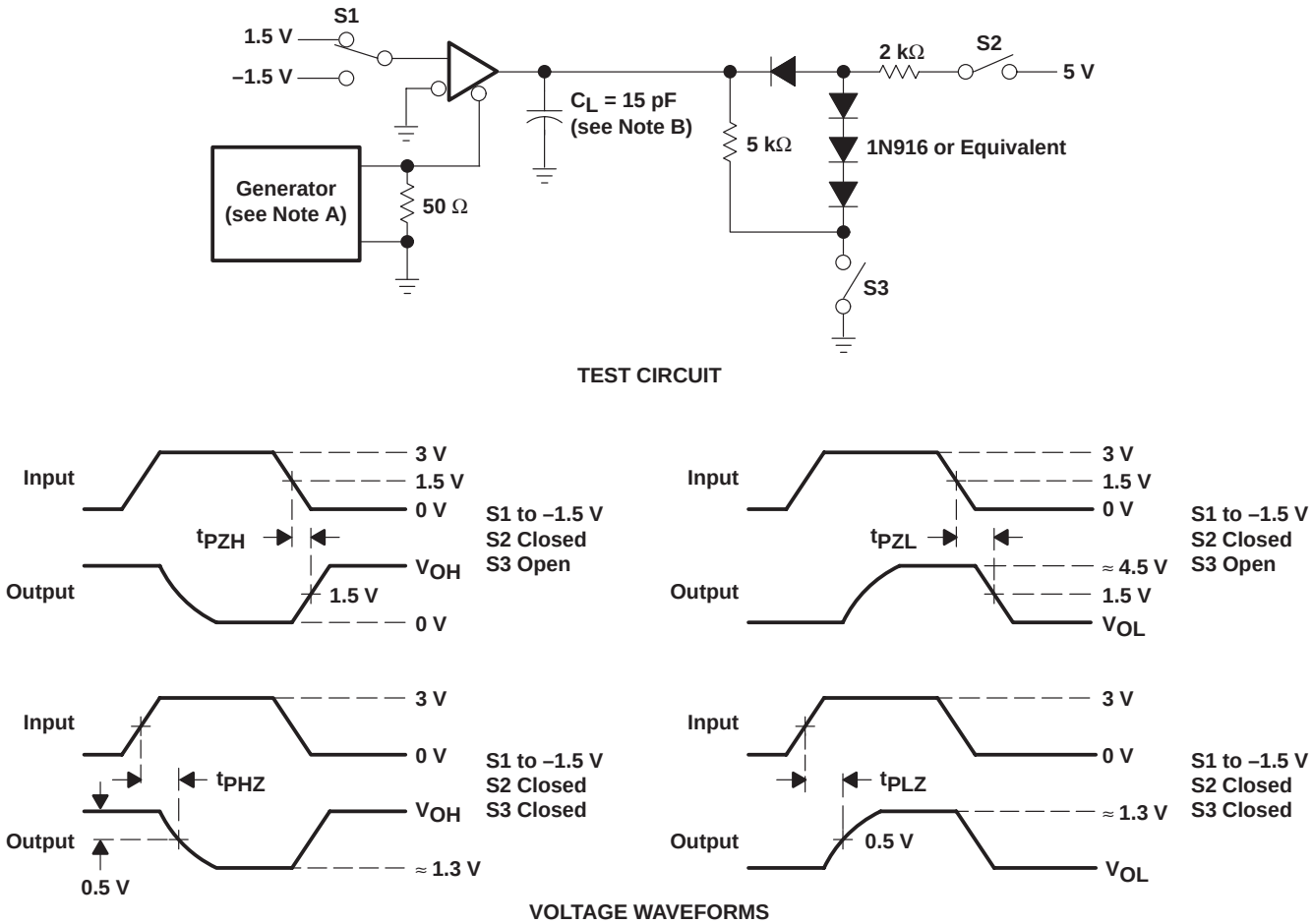
Figure 6. Driver Enable- and Disable-Time Test Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION



NOTES: A. The pulse generator has the following characteristics: PRR ≤ 1 MHz, 50% duty cycle, Z_O = 50 Ω, t_r ≤ 6 ns, t_f ≤ 6 ns.
B. C_L includes probe and jig capacitance.

Figure 7. Receiver Propagation Delay Time Test Circuit and Voltage Waveforms



NOTES: A. The pulse generator has the following characteristics: PRR ≤ 1 MHz, 50% duty cycle, Z_O = 50 Ω, t_r ≤ 6 ns, t_f ≤ 6 ns.
B. C_L includes probe and jig capacitance.

Figure 8. Receiver Output Enable- and Disable-Time Test Circuit and Voltage Waveforms

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